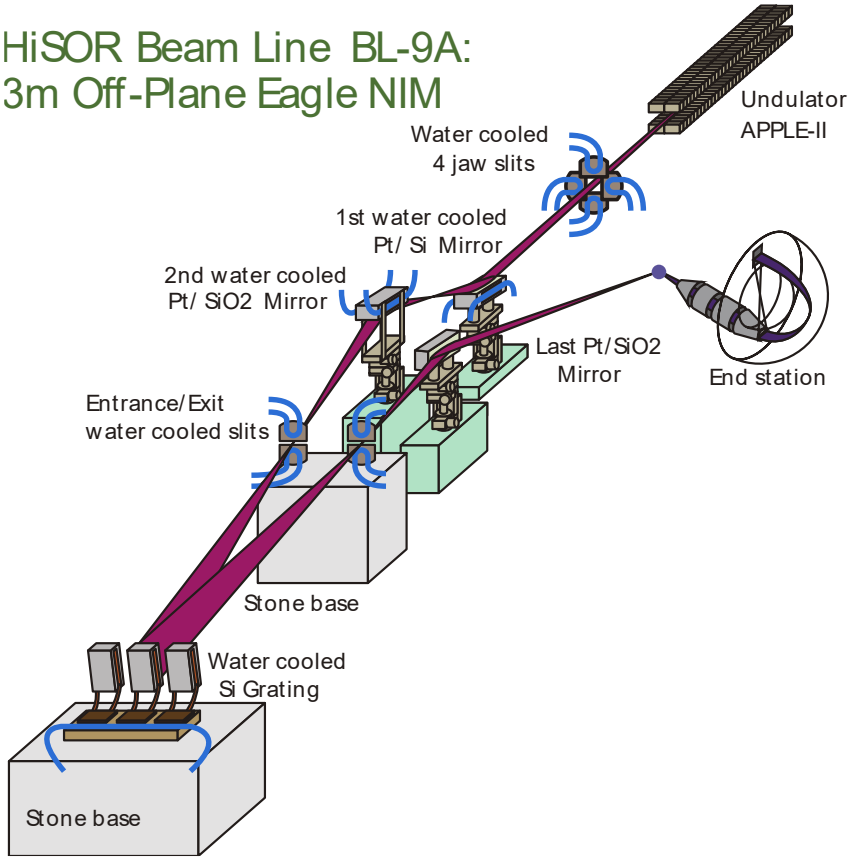
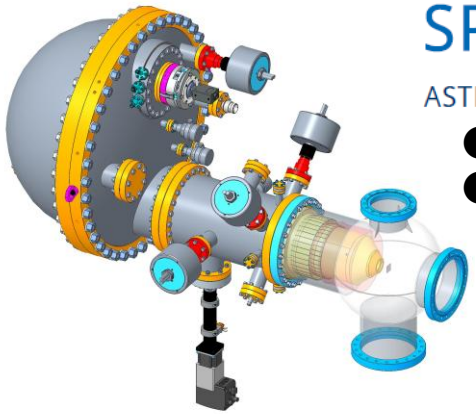
High-resolution angle-resolved photoemission spectroscopy Beamline 9A (BL-9A)



- Photon energy: $h\nu$ ~ 7 eV – 40 eV
- Undulator: APPLE-II (*S*, *P*,C+, C- −pol.)
- Analyzer: SPECS ASTRAIOS 190
- Total ΔE: 3-10 meV ($h\nu$ = 10-30)
- Beam spot: Φ 250 μ m
- Temperature: 10 K – 300 K
- Sample holder: Omicron type
- Surface treatment: Spattering, annealing etc.
- LEED/Auger is available

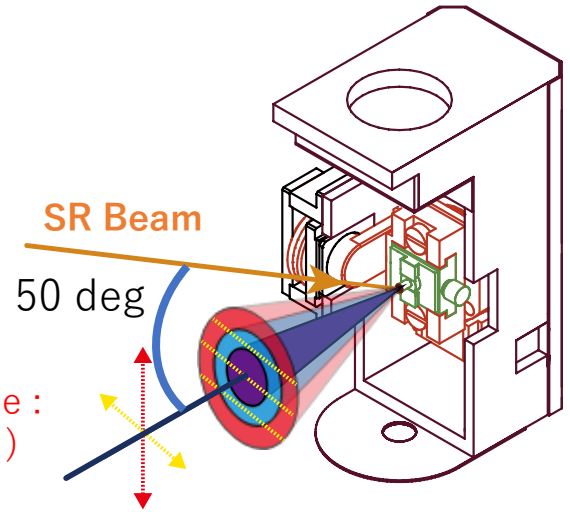
BL-9A SPECS Analyzer



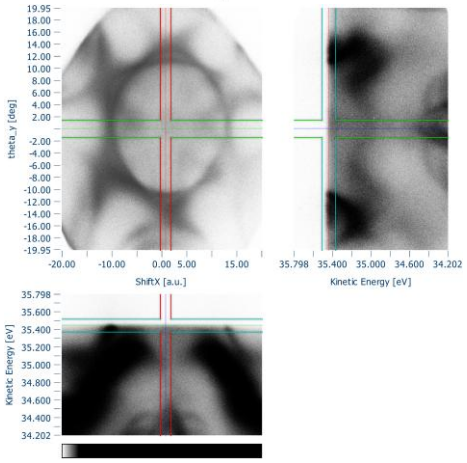
SPECS™

ASTRAIOS 190

- 190mm Hemispherical analyzer
- θ x- θ y Deflector mode scan.



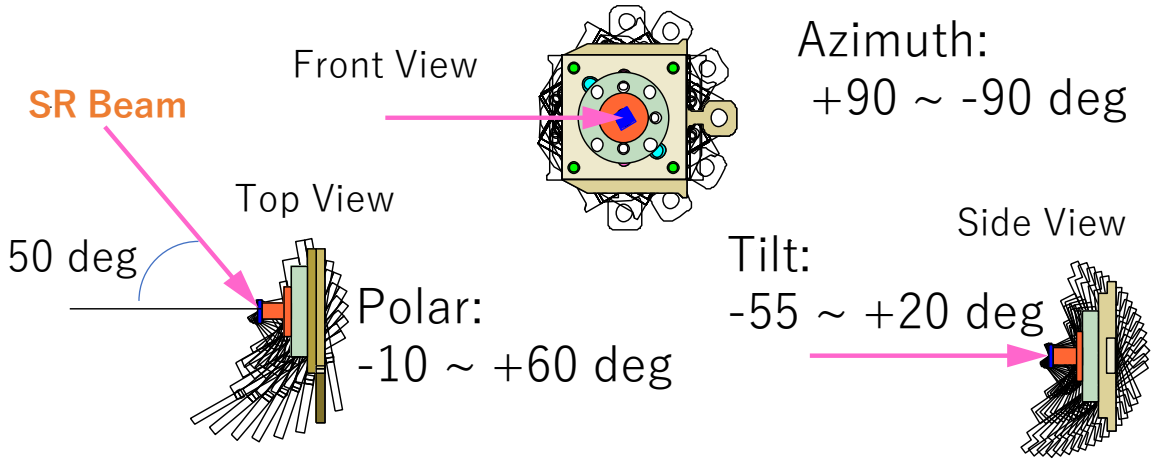
- Deflector ARPES mode : ±9°，±20°，(±30°)



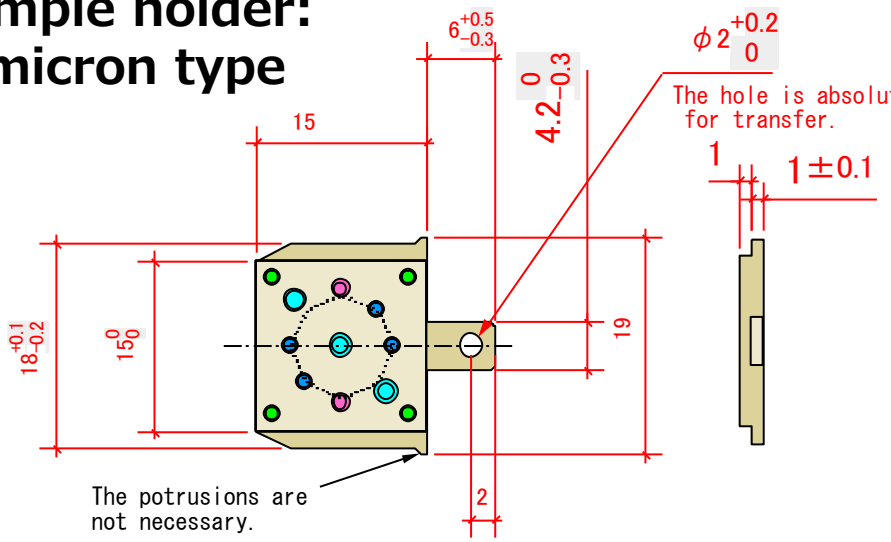
$h\nu$ = 40eV
±20° mode

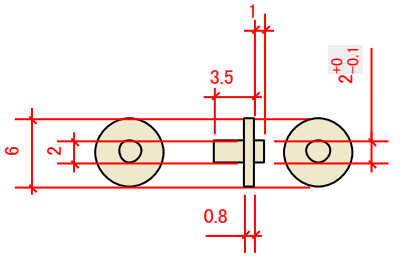
A 2D ARPES map can be measured using a deflector.
On the other hand, it is also possible to obtain a 2D ARPES map by rotating the sample in the conventional manner.

☐ 6-axis sample manipulator

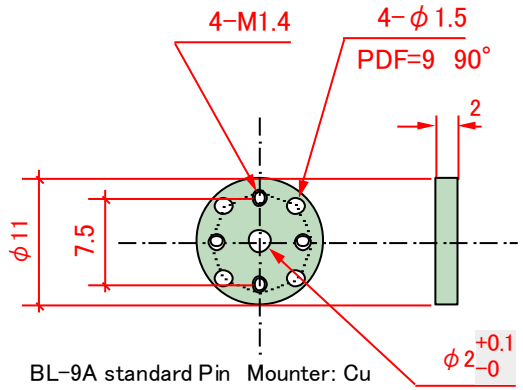


Sample holder: Omicron type



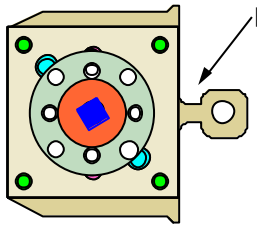


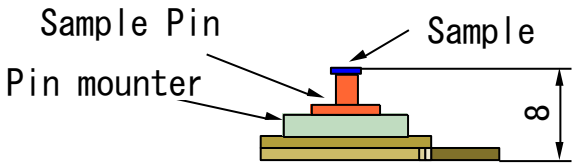
BL-9A standard Sample Pin : Al



BL-9A standard Pin Mounter: Cu

How to mount a sample on the holder





Best sample hight is 8 mm from the bottom.

Holders and mounters from other HiSOR beamlines are also available, unless a special type is required.

Attention